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Foehrenweg 16
P.O Box 62
FL-9496 Balzers
Principality of Liechtenstein
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On the Cover: Visible-light image from a (110) surface of rutile annealed at 1400°C in air. The presence of fine particles on the surface gives rise to the interference pattern. (The image was kindly provided by N. (Ravi) Ravishankar and C. Barry Carter, Department of Chemical Engineering and Materials Science, University of Minnesota, Minneapolis, MN.)

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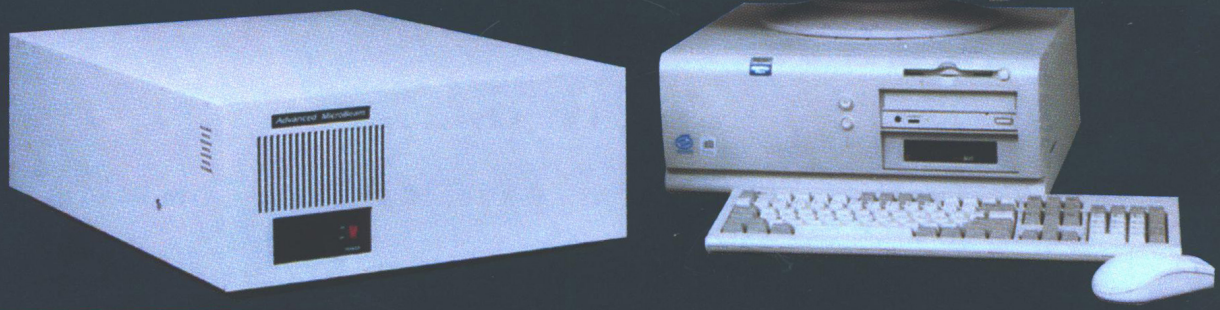

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Telephone: (330) 394-1255 Fax: (330) 394-1834

Website: www.advancedmicrobeam.com · E-Mail: dlesher@advancedmicrobeam.com

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